

AMENDMENTS TO THE CLAIMS

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

1. (Original) An overlay key, comprising:
a first overlay key having a first main overlay pattern and a first auxiliary overlay pattern; and
a second overlay key having a second main overlay pattern and a second auxiliary overlay pattern, the second auxiliary overlay pattern being formed at a location corresponding to the first auxiliary overlay pattern.
2. (Original) The overlay key of claim 1, wherein the first and second overlay keys have a frame shape.
3. (Original) The overlay key of claim 2, wherein the first auxiliary overlay pattern is formed at a corner portion of the first overlay key.
4. (Original) The overlay key of claim 3, wherein a length of the first main overlay pattern is equal to a length of a corresponding side of the second main overlay pattern.
5. (Original) The overlay key of claim 4, wherein the first main overlay pattern is defined by imaginary lines extended from two parallel outside lines of the second main overlay pattern.

6. (Original) The overlay key of claim 1, wherein the first auxiliary overlay pattern includes a plurality of bar patterns spaced apart from each other.

7. (Original) The overlay key of claim 6, wherein the second auxiliary overlay pattern includes a plurality of hole patterns spaced apart from each other.

8. (Original) The overlay key of claim 7, wherein an interval between two adjacent bar patterns is larger than a width of the hole pattern.

9. (Original) The overlay key of claim 6, wherein the second auxiliary overlay pattern includes a plurality of second bar patterns having a smaller width than the bar patterns.

10. (Original) The overlay key of claim 1, wherein the first auxiliary overlay pattern includes a plurality of hole patterns.

11. (Original) The overlay key of claim 10, wherein the second auxiliary overlay pattern includes a plurality of bar patterns.

12. (Original) The overlay key of claim 11, wherein a width of the hole pattern of the first auxiliary overlay pattern is larger than a width of the bar pattern of the second auxiliary overlay pattern.

13. (Original) The overlay key of claim 2, wherein the first auxiliary overlay pattern is formed at a location adjacent to a corner portion of the first overlay key.

14. (Original) The overlay key of claim 13, wherein a length of the first main overlay pattern is equal to a length of a corresponding side of the second main overlay pattern.

15. (Original) The overlay key of claim 14, wherein the first main overlay pattern is defined by imaginary lines extended from two parallel outside lines of the second main overlay pattern.

16. (Original) The overlay key of claim 1, wherein the first and second overlay keys have a substantially rectangular shape.

17. (Original) The overlay key of claim 16, wherein the first auxiliary overlay pattern is formed on a corner portion of the first overlay key.

18. (Original) The overlay key of claim 17, wherein a length of the first main overlay pattern is equal to a length of a corresponding side of the second main overlay pattern.

19. (Original) The overlay key of claim 18, wherein the first main overlay pattern is defined by imaginary lines extended from two parallel outside lines of the second main overlay pattern.

20. (Original) The overlay key of claim 16, wherein the first auxiliary overlay pattern is formed at a location adjacent to a corner portion of the first overlay key.

21. (Original) The overlay key of claim 20, wherein a length of the first main overlay pattern is equal to a length of a corresponding side of the second main overlay pattern.

22. (Original) The overlay key of claim 21, wherein the first main overlay pattern is defined by imaginary lines extended from two parallel outside lines of the second main overlay pattern.

23. (Original) The overlay key of claim 1, wherein the first and second main overlay patterns are for measuring an overlay degree using an optical microscope, and the first and second auxiliary overlay patterns are for measuring an overlay degree using an in-line SEM (scanning electron microscope).

24-50. (Cancel)

51. (New) An overlay key, comprising:

a first overlay key on a first layer having a first main overlay pattern and a first auxiliary overlay pattern; and

a second overlay key on a second layer above the first layer, having a second main overlay pattern and a second auxiliary overlay pattern,

wherein, when viewed from above, at least some portion of the second auxiliary overlay pattern directly overlies at least some portion of the first auxiliary overlay pattern.

52. (New) The overlay key of claim 51, wherein the first auxiliary overlay pattern includes a plurality of bar patterns spaced apart from each other.

53. (New) The overlay key of claim 52, wherein the second auxiliary overlay pattern includes a plurality of hole patterns spaced apart from each other.

54. (New) The overlay key of claim 53, wherein an interval between two adjacent bar patterns is larger than a width of the hole pattern.

55. (New) The overlay key of claim 52, wherein the second auxiliary overlay pattern includes a plurality of second bar patterns having a smaller width than the bar patterns.

56. (New) The overlay key of claim 51, wherein the first auxiliary overlay pattern includes a plurality of hole patterns.

57. (Original) The overlay key of claim 56, wherein the second auxiliary overlay pattern includes a plurality of bar patterns.

58. (Original) The overlay key of claim 57, wherein a width of the hole pattern of the first auxiliary overlay pattern is larger than a width of the bar pattern of the second auxiliary overlay pattern.

AMENDMENTS TO THE DRAWINGS

The attached sheets of drawings include changes to FIGs.1A-2B. These sheets replace the original sheets including FIGs.1A-2B. FIGs 1A-2B have been amended to change the label “Related Art” to read “Prior Art.”

Attachments: Replacement Sheets
Annotated Sheets Showing Changes